

Title (en)

X-RAY GENERATION DEVICE AND METHOD, AND SAMPLE MEASUREMENT SYSTEM

Title (de)

RÖNTGENERZEUGUNGSVORRICHTUNG UND -VERFAHREN SOWIE PROBENMESSSYSTEM

Title (fr)

DISPOSITIF ET PROCÉDÉ DE GÉNÉRATION DE RAYONS X, ET SYSTÈME DE MESURE D'ÉCHANTILLON

Publication

**EP 3346484 A1 20180711 (EN)**

Application

**EP 16841334 A 20160726**

Priority

- JP 2015170101 A 20150831
- JP 2015214418 A 20151030
- JP 2016071811 W 20160726

Abstract (en)

Provided are: an X-ray generating device, an X-ray generating method, and a sample measurement system which have an extremely simple device configuration and are capable of selectively generating a linear or dot-like X-ray beam. The X-ray generating device (10) comprises an electron generator (24) and a rotating anticathode (26) which are fixed arranged in a positional relationship in which an electron source (32) and a circumferential surface portion (38) face one another while a rotation axis (36) is tilted with respect to a first direction (Z direction) and a second direction (X direction).

IPC 8 full level

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CPC (source: EP KR US)

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**H01J 2235/066** (2013.01 - EP KR)

Designated contracting state (EPC)

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Designated extension state (EPC)

BA ME

DOCDB simple family (publication)

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MA 43905 A 20181205; WO 2017038302 A1 20170309

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